


<b>Search Notes</b>  	<b>Application/Control No.</b>  10517665	<b>Applicant(s)/Patent Under Reexamination</b>  SHIRAKURA, SHIGEO
	<b>Examiner</b>  DAVID WEISZ	<b>Art Unit</b>  1797

SEARCHED			
Class	Subclass	Date	Examiner
422	62-64	12/17/2008	/DW/

SEARCH NOTES		
Search Notes	Date	Examiner
EAST text search (see search history)	12/17/2008	/DW/
Inventor name search in PALM	12/17/2008	/DW/
Consultation with examiner Arlen Soderquist AU 1797 (text searching)	12/17/2008	/DW/

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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